

**Notice of References Cited**

Application/Control No.

09/499,037

Applicant(s)/Patent Under  
Reexamination  
AIHARA ET AL.

Examiner

Johannes P Mondt

Art Unit

2826

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Matsushashi, H. et al., "Optimum Electrode Materials for Ta2O5 Capacitors for High- and Low- Temperature Processes", Jpn. J Appl. Phys., Volume 53, pp. 1293-1297 (1994) (made of record by Applicant in Response filed 09/22/2003)
	V	
	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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